

# Grazing-Incidence EUV Collector Coated by DLC

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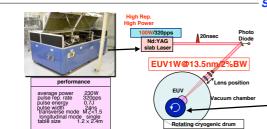
Plasma-debris damages a EUV-collection-mirror and degrades its reflectivity. This is a critical issue for most of plasma EUV sources and its mitigation is required.

In this paper, we propose a new approach to mitigate the debris effects. In generally, the plasma-debris occurs deposition and/or sputtering on the mirror surface, but the latter is more serious.

nt mirror with a very hard coat for grazing-incidence EUV collectors. For this hard coat, new diamond-like carbon (DLC) film is proposed.

The DLC film formed by Ar cluster ion beam assisted deposition, which was developed in our laboratory (LASTI), has the high hardness of 50GPa.

To evaluate the DLC coating as EUV mirror, we measured 1) its reflectivity by using our SR(Synchrotron Radiation) facility "NewSUBARU", 2) its focusing performance of the cylindrical mirror and 3) its erosion rate (compared with Ru coating) by using our Xe - LPP source



Ref.) S.Amano et al., IEEE J. QE-37,296(2001).

#### Solid Xe target - LPP EUV Source-

Ref.) S.Amano et al, Rev.Sci.Inst.,vol.77,063114(2006).

# **Performance** EUV @13.5nm2%BW 1) CE ; 0.9%/2πsr

2) 1 W continuous generation

Ref.) S.Amano et al, Appl.Phys.B,vol.101,213(2010).

#### **Debris**

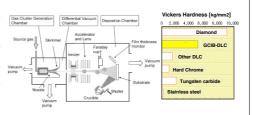
Major component; fast ions (<6keV) Ref.) S.Amano et al, Rev.Sci.Inst.,vol.81,023104(2010).

# GCIB-DLC (High Hardness film)

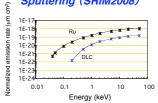
Diamond-like carbon (DLC) films with high hardness were developed in our laboratory (LASTI), which formed by Ar gas cluster ion beam (GCIB) assisted deposition.

The deposition was performed with the evaporation of  $C_{60}$  as carbon source during the irradiation of Ar cluster ion beam. This is useful to form hard DLC films, as the bombardments induced high-pressure and high-temperature effects at the impact surface, and ultra low energy effects.

The hardness of 50GPa was obtained This value was approximately two times higher than that of films deposited with conventional methods



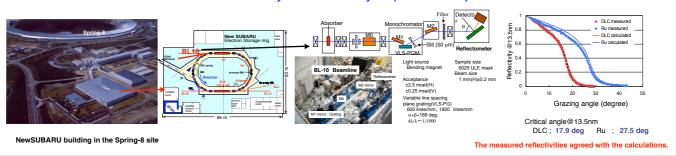
#### Erosion rate calculated for Xe ion Sputtering (SRIM2008)



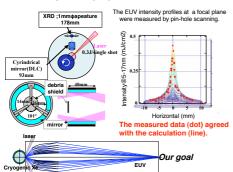
The erosion rate at the DLC were 1 $\sim$ 3 order of magnitude less than that at Ru.

A sputtering-resistant mirror at the DLC.

### Reflectivity measurement by SR (NewSUBARU)



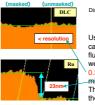
#### Focusing test by cylindrical DLC mirror



Nested Walter DLC mirrors

Walter mirror is goal, but the simple cylindrical mirror was tested at first.

#### Measurement of depth sputtered by Xe plasma (AFM)



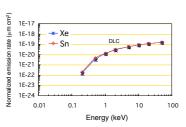
DLC and Ru test samples were exposed to Xe plasma.

Distance :100mm, incidence angle: 0degree Laser 0.3J/ 196000shots

Using a sputtering yield calculated by SRIM and an ion flux measured, sputtered depth were calculated to be 0.3nm at DLC and 21nm at Ru mirror respectively. The measured results agreed with the calculations

The erosion rate by Xe ions for the DLC coating was an order of magnitude less than that for the Ru

#### Erosion rate calculated for Sn ion sputtering (SRIM2008)



The erosion rate by Sn ions was same as by Xe ions.

In the test of mirror reflectivity and focusing for the new DLC coating with the high hardness, the measured results were in good agreement with the calculations. These indicate the DLC coating can be used for EUV mirror. The measured erosion rate by Xe ions for the DLC coating was an order of magnitude less than that for the Ru coating. The SRIM code calculation showed that the erosion rate by Sn ions was same as by Xe ions. We conclude that the hard DLC mirror is useful as a sputtering-resistant mirror for not only Xe but also Sn - LPP source.